Features

- Fast read access time – 55ns
- Low-power CMOS operation
    - 100µA max standby
    - 35mA max active at 5MHz
- JEDEC standard packages
    - 44-lead PLCC
- Direct upgrade from 512Kbit and 1Mbit (Atmel® AT27C516 and AT27C1024) EPROMs
- 5V ± 10% supply
- High-reliability CMOS technology
    - 2,000V ESD protection
    - 200mA latchup immunity
- Rapid programming algorithm – 50µs/word (typical)
- CMOS- and TTL-compatible inputs and outputs
- Integrated product identification code
- Industrial temperature range

2Mb (128K x 16) One-time Programmable, Read-only Memory

Atmel AT27C2048

1. Description

The **Atmel** AT27C2048 is a low-power, high-performance 2,097,152-bit, one-time programmable, read-only memory (OTP EPROM) organized as 128K by 16 bits. It requires a single 5V power supply in normal read mode operation. Any word can be accessed in less than 55 ns, eliminating the need for speed-reducing WAIT states. The x16 organization makes this part ideal for high-performance, 16- and 32-bit microprocessor systems.

In read mode, the AT27C2048 typically consumes 15mA. Standby mode supply current is typically less than 10µA.

The AT27C2048 is available in an industry-standard, JEDEC-approved, one-time programmable (OTP) PLCC package. The device features two-line control ($\overline{CE}$, $\overline{OE}$) to eliminate bus contention in high-speed systems.

With high-density, 128K word storage capability, the AT27C2048 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

The AT27C2048 has additional features that ensure high quality and efficient production use. The rapid programming algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 50 µs/word. The Integrated product identification code electronically identifies the device and manufacturer. This feature is used by industry-standard programming equipment to select the proper programming algorithms and voltages.

2. Pin configurations

Pin name	Function
A0 – A16	Addresses
O0 – O15	Outputs
$\overline{CE}$	Chip enable
$\overline{OE}$	Output enable
$\overline{PGM}$	Program strobe
NC	No connect
DC	Don't connect

Note: Both GND pins must be connected.

44-lead PLCC
Top view
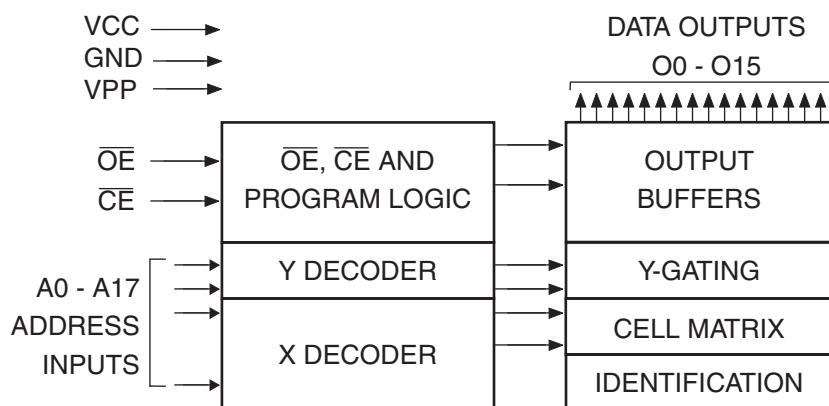
Note: PLCC package pins 1 and 23 are "don't connect."

3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device nonconformance. At a minimum, a 0.1µF, high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7µF bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

Figure 3-1.   Block diagram

4. Absolute maximum ratings*

Temperature under bias . . . . –55°C to +125°C

Storage temperature . . . . –65°C to +150°C

Voltage on any pin with
respect to ground . . . . –2.0V to +7.0V[1]

Voltage on A9 with
respect to ground . . . . –2.0V to +14.0V[1]

V_{PP} supply voltage with
respect to ground . . . . –2.0V to +14.0V[1]

*NOTICE: Stresses beyond those listed under "Absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1.   Maximum voltage is –0.6V DC, which may undershoot to –2.0V for pulses of less than 20ns. Maximum output pin voltage is V_{CC} + 0.75V DC, which may overshoot to +7.0V for pulses of less than 20ns.

5. DC and AC characteristics

Table 5-1.   Operating modes

Mode/Pin	$\overline{CE}$	$\overline{OE}$	$\overline{PGM}$	Ai	V_{PP}	Outputs
Read	V_{IL}	V_{IL}	X[1]	Ai	X[1]	D_{OUT}
Output disable	X	V_{IH}	X	X	X	High Z
Standby	V_{IH}	X	X	X	X[5]	High Z
Rapid program[2]	V_{IL}	V_{IH}	V_{IL}	Ai	V_{PP}	D_{IN}
PGM verify	V_{IL}	V_{IL}	V_{IH}	Ai	V_{PP}	D_{OUT}
PGM inhibit	V_{IH}	X	X	X	V_{PP}	High Z
Product identification[4]	V_{IL}	V_{IL}	X	A9 = V_H[3] A0 = V_{IH} or V_{IL} A1 - A16 = V_{IL}	V_{CC}	Identification code

Notes: 1.   X can be V_{IL} or V_{IH}.

2.   Refer to the programming characteristics.

3. V_H = 12.0 ± 0.5V.

4.   Two identifier words may be selected. All Ai inputs are held low (V_{IL}), except A9, which is set to V_H, and A0, which is toggled low (V_{IL}) to select the manufacturer's identification word and high (V_{IH}) to select the device code word.

5.   Standby V_{CC} current (I_{SB}) is specified with V_{PP} = V_{CC}. V_{CC} > V_{PP} will cause a slight increase in I_{SB}.

Table 5-2.   DC and AC operating conditions for read operation

|	Atmel AT27C2048	
	-55	-90
Industrial operating temperature (case)	–40°C - 85°C	–40°C - 85°C
V_{CC} power supply	5V ± 10%	5V ± 10%

Table 5-3. DC and operating characteristics for read operation

Symbol	Parameter	Condition	Min	Max	Units
I_{LI}	Input load current	V_{IN} = 0V to V_{CC}		± 1	µA
I_{LO}	Output leakage current	V_{OUT} = 0V to V_{CC}		± 5	µA
I_{PP1} [2]	V_{PP} [1] read/standby current	V_{PP} = V_{CC}		10	µA
I_{SB}	V_{CC} [1] standby current	I_{SB1} (CMOS) $\overline{CE}$ = V_{CC} ± 0.3V		100	µA
		I_{SB2} (TTL) $\overline{CE}$ = 2.0 to V_{CC} + 0.5V		1	mA
I_{CC}	V_{CC} active current	f = 5MHz, I_{OUT} = 0mA, $\overline{CE}$ = V_{IL}		35	mA
V_{IL}	Input low voltage		-0.6	0.8	V
V_{IH}	Input high voltage		2.0	V_{CC} + 0.5	V
V_{OL}	Output low voltage	I_{OL} = 2.1mA		0.4	V
V_{OH}	Output high voltage	I_{OH} = -400µA	2.4		V
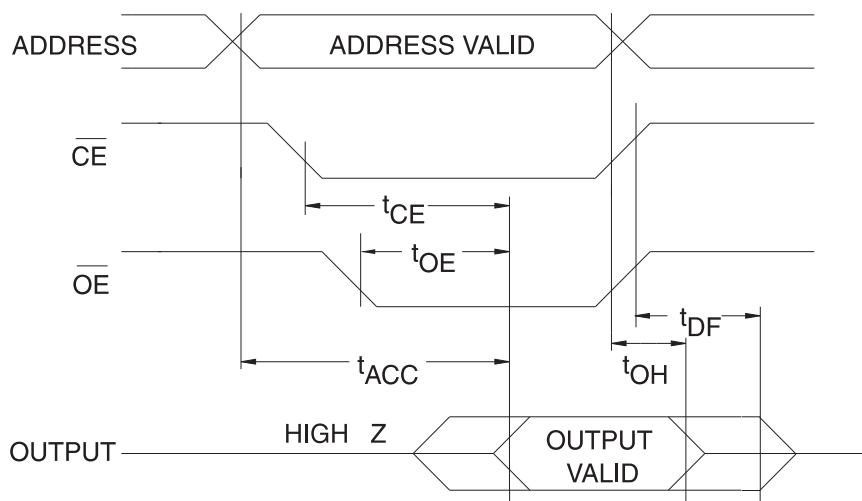
Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP}, and removed simultaneously with or after V_{PP}.

2. V_{PP} may be connected directly to V_{CC}, except during programming. The supply current would then be the sum of I_{CC} and I_{PP}.

Table 5-4. AC characteristics for read operation

| Symbol	Parameter	Condition	Atmel AT27C2048 -55 Min	Atmel AT27C2048 -55 Max	Atmel AT27C2048 -90 Min	Atmel AT27C2048 -90 Max	Units
t_{ACC} [3]	Address to output delay	$\overline{CE}$ = $\overline{OE}$ = V_{IL}		55		90	ns
t_{CE} [2]	$\overline{CE}$ to output delay	$\overline{OE}$ = V_{IL}		55		90	ns
t_{OE} [2][3]	$\overline{OE}$ to output delay	$\overline{CE}$ = V_{IL}		20		35	ns
t_{DF} [4][5]	$\overline{OE}$ or $\overline{CE}$ high to output float, whichever occurred first			20		20	ns
t_{OH} [4]	Output hold from address, $\overline{CE}$ or $\overline{OE}$, whichever occurred first		7		0		ns
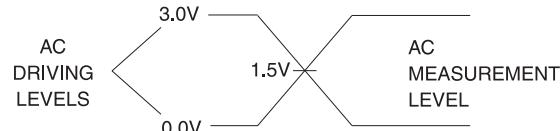
Note: 2, 3, 4, 5. See the AC waveforms for read operation diagram.

Figure 5-1. AC waveforms for read operation[1]

ADDRESS — ADDRESS VALID

$\overline{CE}$

t_{CE}

t_{OE}

$\overline{OE}$

t_{DF}

t_{ACC}

t_{OH}

OUTPUT — HIGH Z — OUTPUT VALID

Notes: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.

2. $\overline{OE}$ may be delayed up to t_{CE} – t_{OE} after the falling edge of $\overline{CE}$ without impact on t_{CE}.

3. $\overline{OE}$ may be delayed up to t_{ACC} – t_{OE} after the address is valid without impact on t_{ACC}.

4. This parameter is only sampled, and is not 100% tested.

5. Output float is defined as the point when data is no longer driven.
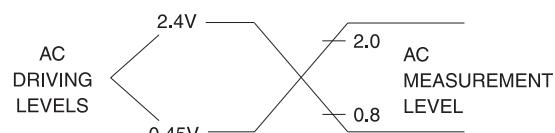
Figure 5-2. Input test waveforms and measurement levels

For –55 devices only:

AC DRIVING LEVELS — 3.0V — 1.5V — 0.0V — AC MEASUREMENT LEVEL
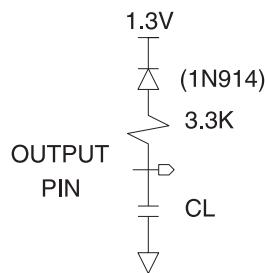
t_R, $t_F <$ 5ns (10% to 90%)

For –90 devices:

AC DRIVING LEVELS — 2.4V — 0.45V — 2.0 — 0.8 — AC MEASUREMENT LEVEL

t_R, $t_F <$ 20ns (10% to 90%)

Figure 5-3.   Output test load
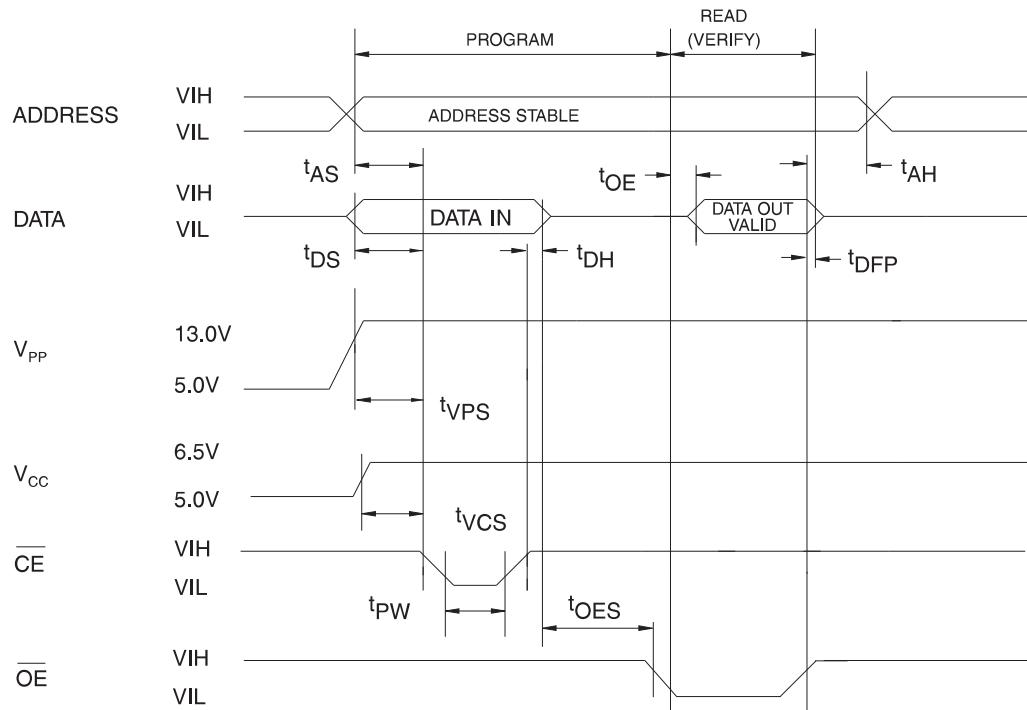
Note: CL = 100pF including jig capacitance, except for the -55 devices, where CL = 30pF.

Table 5-5.   Pin capacitance

Symbol	Typ	Max	Units	Conditions
C_{IN}	4	10	pF	$V_{IN} = 0V$
C_{OUT}	8	12	pF	$V_{OUT} = 0V$

Note: Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.

Figure 5-4.   Programming waveforms[1]

Notes: 1.   The input timing reference is 0.8V for V_{IL} and 2.0V for V_{IH}.

2. t_{OE} and t_{DFP} are characteristics of the device, but must be accommodated by the programmer.

3.   When programming the Atmel AT27C2048, a 0.1µF capacitor is required across V_{PP} and ground to suppress spurious voltage transients.

Table 5-6.   DC programming characteristics

$T_A = 25 \pm 5°C$, $V_{CC} = 6.5 \pm 0.25V$, $V_{PP} = 13.0 \pm 0.25V$

Symbol	Parameter	Test conditions	Limits Min	Limits Max	Units
I_{LI}	Input load current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA
V_{IL}	Input low level		-0.6	0.8	V
V_{IH}	Input high level		2.0	$V_{CC} + 0.5$	V
V_{OL}	Output low voltage	$I_{OL} = 2.1mA$		0.4	V
V_{OH}	Output high voltage	$I_{OH} = -400μA$	2.4		V
I_{CC2}	V_{CC} supply current (program and verify)			50	mA
I_{PP2}	V_{PP} supply current	$\overline{CE} = V_{IL}$		30	mA
V_{ID}	A9 product identification voltage		11.5	12.5	V

Table 5-7.   AC programming characteristics

$T_A = 25 \pm 5°C$, $V_{CC} = 6.5 \pm 0.25V$, $V_{PP} = 13.0 \pm 0.25V$

Symbol	Parameter	Test Conditions[1]	Limits Min	Limits Max	Units
t_{AS}	Address setup time		2		μs
t_{OES}	$\overline{OE}$ setup time	Input rise and fall times (10% to 90%) 20ns	2		μs
t_{DS}	Data setup time		2		μs
t_{AH}	Address hold time		0		μs
t_{DH}	Data hold time	Input pulse levels 0.45V to 2.4V	2		μs
t_{DFP}	$\overline{OE}$ high to output float delay[2]		0	130	ns
t_{VPS}	V_{PP} setup time	Input timing reference level 0.8V to 2.0V	2		μs
t_{VCS}	V_{CC} setup time		2		μs
t_{PW}	$\overline{PGM}$ program pulse width[3]	Output timing reference level 0.8V to 2.0V	47.5	52.5	μs
t_{OE}	Data valid from $\overline{OE}$			150	ns
t_{PRT}	V_{PP} pulse rise time during programming		50		ns

Notes: 1. V_{CC} must be applied simultaneouslywithor before V_{PP} and removed simultaneously with or after V_{PP}.
2. This parameter is only sampled, and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.
3. Program pulse width tolerance is 50μs ± 5%.
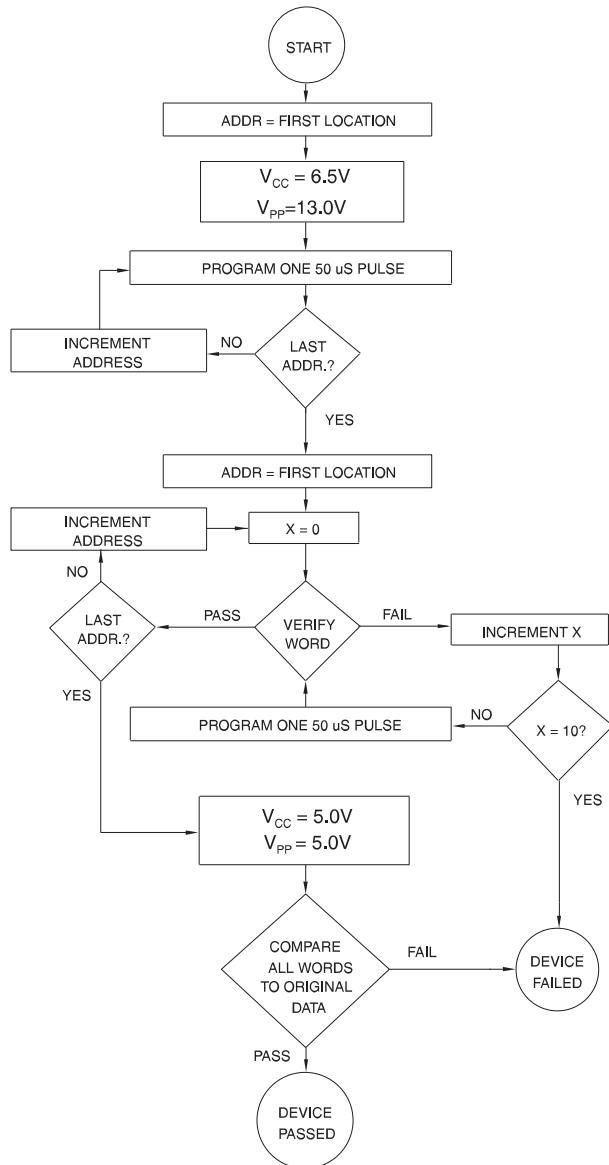
Table 5-8.   The Atmel AT27C2048 intergrated product identification code

Codes	Pins A0	O15–O8	O7	O6	O5	O4	O3	O2	O1	O0	Hex data
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device type	1	0	1	1	1	1	0	1	1	1	00F7

6. Rapid programming algorithm

A 50µs $\overline{CE}$ pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and V_{PP} is raised to 13.0V. Each address is first programmed with one 50µs $\overline{CE}$ pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 50µs pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked. V_{PP} is then lowered to 5.0V and V_{CC} to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.

Figure 6-1.   Rapid programming algorithm

7. Ordering Information
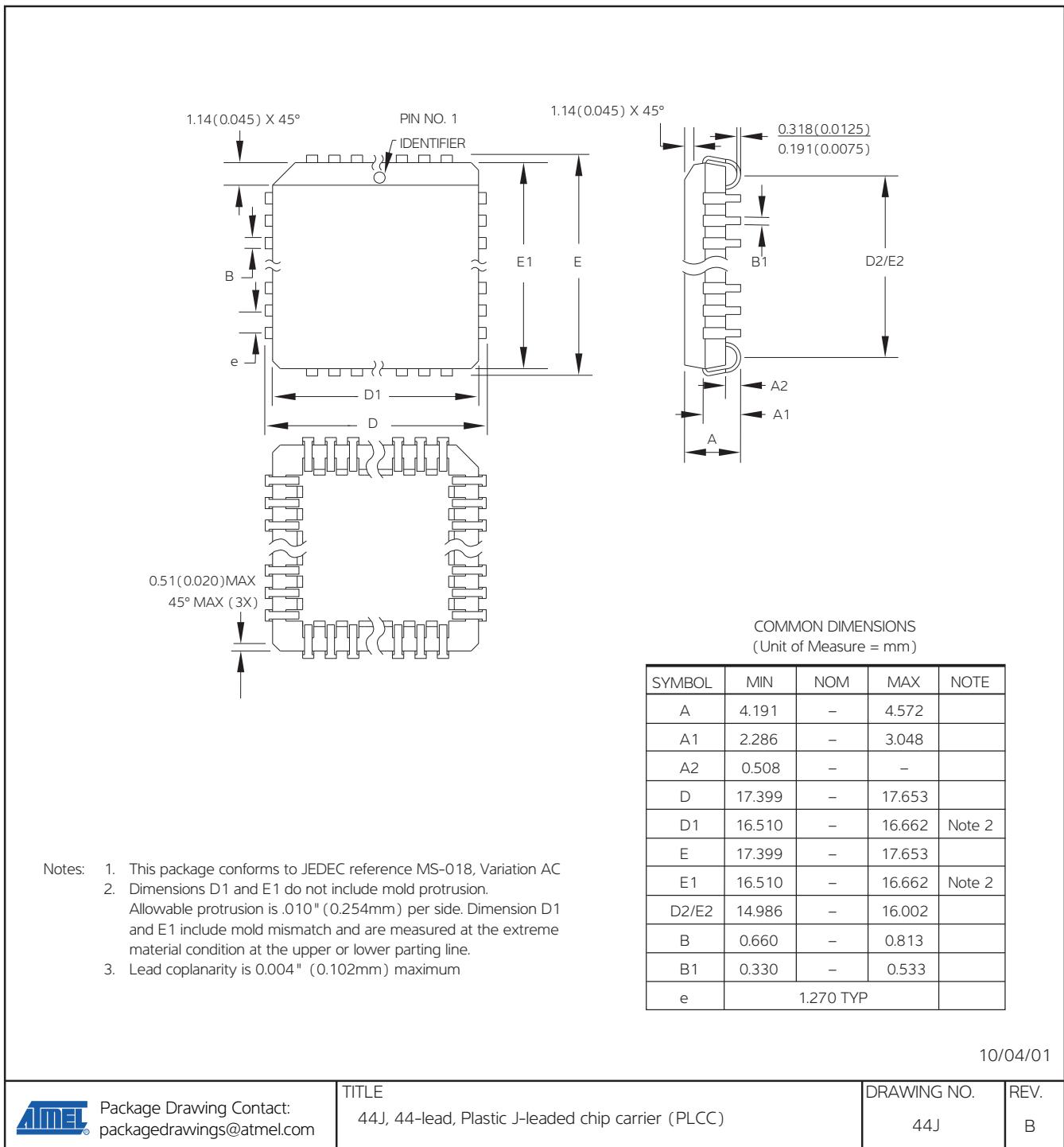
Green package (Pb/halide-free)

t_{ACC} (ns)	I_{CC} (mA)		Atmel ordering code	Package	Lead finish	Operation range
	Active	Standby				
55	35	0.1	AT27C2048-55JU	44J	Matte tin	Industrial (-40°C to 85°C)
90	35	0.1	AT27C2048-90JU	44J	Matte tin	Industrial (-40°C to 85°C)

Package type	
44J	44-lead, plastic, J-leaded chip carrier (PLCC)

8. Packaging information

44J – PLCC

1.14(0.045) X 45°

PIN NO. 1
IDENTIFIER

1.14(0.045) X 45°

0.318(0.0125)
0.191(0.0075)

E1 E

B

e

D1

D

B1

D2/E2

A2

A1

A

0.51(0.020)MAX
45° MAX (3X)

COMMON DIMENSIONS
(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
A	4.191	–	4.572	
A1	2.286	–	3.048	
A2	0.508	–	–	
D	17.399	–	17.653	
D1	16.510	–	16.662	Note 2
E	17.399	–	17.653	
E1	16.510	–	16.662	Note 2
D2/E2	14.986	–	16.002	
B	0.660	–	0.813	
B1	0.330	–	0.533	
e	1.270 TYP			

Notes: 1. This package conforms to JEDEC reference MS-018, Variation AC
2. Dimensions D1 and E1 do not include mold protrusion.
Allowable protrusion is .010" (0.254mm) per side. Dimension D1
and E1 include mold mismatch and are measured at the extreme
material condition at the upper or lower parting line.
3. Lead coplanarity is 0.004" (0.102mm) maximum

10/04/01

	Package Drawing Contact: packagedrawings@atmel.com	TITLE 44J, 44-lead, Plastic J-leaded chip carrier (PLCC)	DRAWING NO. 44J	REV. B

9. Revision history

Doc. Rev.	Date	Comments
0632G	04/2011	Remove PDIP and VSOP packages Add lead finish to ordering information
0632F	12/2007	